

IRF730/731/732/733

IRFP330/331/332/333

N-CHANNEL

POWER MOSFETS

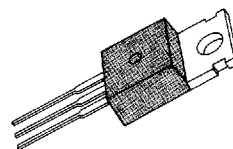
FEATURES

- Lower $R_{DS(on)}$
- Improved inductive ruggedness
- Fast switching times
- Rugged polysilicon gate cell structure
- Lower input capacitance
- Extended safe operating area
- Improved high temperature reliability

PRODUCT SUMMARY

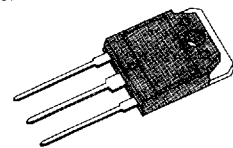
Part Number	V_{DS}	$R_{DS(on)}$	I_D
IRF730/IRFP330	400V	1.0Ω	5.5A
IRF731/IRFP331	350V	1.0Ω	5.5A
IRF732/IRFP332	400V	1.5Ω	4.5A
IRF733/IRFP333	350V	1.5Ω	4.5A

TO-220



IRF730/731/732/733

TO-3P



IRFP330/331/332/333

MAXIMUM RATINGS

Characteristics	Symbol	IRF730 IRFP330	IRF731 IRFP331	IRF732 IRFP332	IRF733 IRFP333	Unit
Drain-Source Voltage (1)	V_{DSS}	400	350	400	350	Vdc
Drain-Gate Voltage ($R_{GS}=1.0M\Omega$)(1)	V_{DGR}	400	350	400	350	Vdc
Gate-Source Voltage	V_{GS}	± 20				Vdc
Continuous Drain Current $T_C=25^\circ C$	I_D	5.5	5.5	4.5	4.5	Adc
Continuous Drain Current $T_C=100^\circ C$	I_D	3.5	3.5	3.0	3.0	Adc
Drain Current—Pulsed (3)	I_{DM}	32	32	18	18	Adc
Gate Current—Pulsed	I_{GM}	± 1.5				Adc
Single Pulsed Avalanche Energy (4)	E_{AS}	290				mJ
Avalanche Current	I_{AS}	5.5				A
Total Power Dissipation @ $T_C=25^\circ C$ Derate above $25^\circ C$	P_D	75 0.6				Watts W/ $^\circ C$
Operating and Storage Junction to Case	T_J, T_{stg}	-55 to 150				$^\circ C$
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	T_L	300				$^\circ C$

Notes: (1) $T_J=25^\circ C$ to $150^\circ C$

(2) Pulse test: Pulse width $\leq 300\mu s$, Duty Cycle $\leq 2\%$

(3) Repetitive rating: Pulse with limited by max. junction temperature

(4) $L=17\text{ mH}$, $V_{dd}=50V$, $R_G=25\Omega$, Starting $T_J=25^\circ C$

IRF730/731/732/733 IRFP330/331/332/333

N-CHANNEL POWER MOSFETS

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ELECTRICAL CHARACTERISTICS (T_C=25°C unless otherwise specified)

Symbol	Characteristic	Min	Typ	Max	Units	Test Conditions
BV _{DSS}	Drain-Source Breakdown Voltage IRF730/IRFP330 IRF732/IRFP332	400	—	—	V	V _{GS} =0V I _D =250μA
	IRF731/IRFP331 IRF733/IRFP333	350	—	—	V	
V _{GS(th)}	Gate Threshold Voltage	2.0	—	4.0	V	V _{DS} =V _{GS} , I _D =250μA
I _{GSS}	Gate-Source Leakage Forward	—	—	100	nA	V _{GS} =20V
I _{GSS}	Gate-Source Leakage Reverse	—	—	-100	nA	V _{GS} =-20V
I _{DSS}	Zero Gate Voltage Drain Current	—	—	250	μA	V _{DS} =Max. Rating, V _{GS} =0V
		—	—	1000	μA	V _{DS} =Max. Rating×0.8, V _{GS} =0V, T _C =125°C
I _{D(on)}	On-State Drain-Source Current (2) IRF730/IRFP330 IRF731/IRFP331	5.5	—	—	A	V _{DS} ≥8.2V, V _{GS} =10V
	IRF732/IRFP332 IRF733/IRFP333	4.5	—	—	A	
R _{DS(on)}	Static Drain-Source On-State Resistance (2) IRF730/IRFP330 IRF731/IRFP331	—	0.8	1.0	Ω	V _{GS} =10V, I _D =3.0A
	IRF732/IRFP332 IRF733/IRFP333	—	1.0	1.5	Ω	
g _{fs}	Forward Transconductance (2)	2.9	4.4	—	∅	V _{DS} ≥50V, I _D =3.0A
C _{iss}	Input Capacitance	—	780	—	pF	V _{GS} =0V, V _{DS} =25V, f=1.0MHz
C _{oss}	Output Capacitance	—	99	—	pF	
C _{rss}	Reverse Transfer Capacitance	—	43	—	pF	
t _{d(on)}	Turn-On Delay Time	—	11	17	ns	V _{DD} =0.5BV _{DSS} , I _D =5.5A, Z _O =12Ω (MOSFET switching times are essentially independent of operating temperature)
t _r	Rise Time	—	19	29	ns	
t _{d(off)}	Turn-Off Delay Time	—	37	56	ns	
t _f	Fall Time	—	16	24	ns	
Q _g	Total Gate Charge (Gate-Source Plus Gate-Drain)	—	18	30	nC	V _{GS} =10V, I _D =5.5A, V _{DS} =0.8 Max. Rating (Gate charge is essentially independent of operating temperature.)
Q _{gs}	Gate-Source Charge	—	40	—	nC	
Q _{gd}	Gate-Drain ("Miller") Charge	—	14	—	nC	

THERMAL RESISTANCE

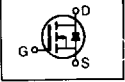
Symbol	Characteristic		IRF730-3	IRFP330-3	Unit	
R _{thJC}	Junction-to-Case	MAX	1.67	1.67	K/W	
R _{thCS}	Case-to-Sink	TYP	0.50	0.24	K/W	Mounting surface flat, smooth, and greased
R _{thJA}	Junction-to-Ambient	MAX	80	40	K/W	Free Air Operation

Notes: (1) T_J=25°C to 150°C

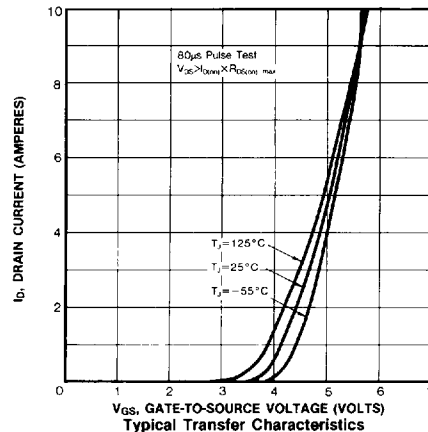
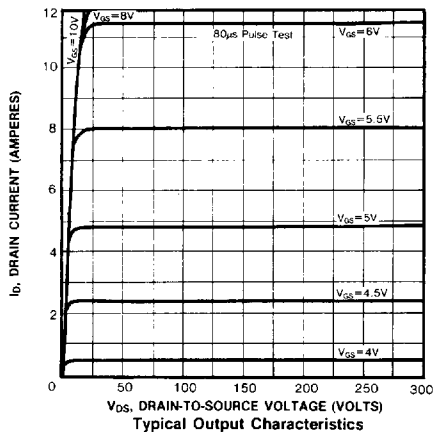
(2) Pulse test: Pulse width≤300μs, Duty Cycle≤2%

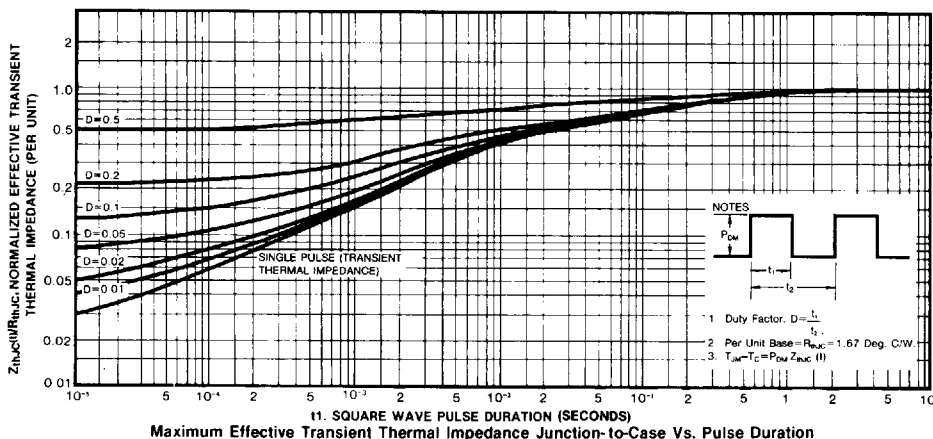
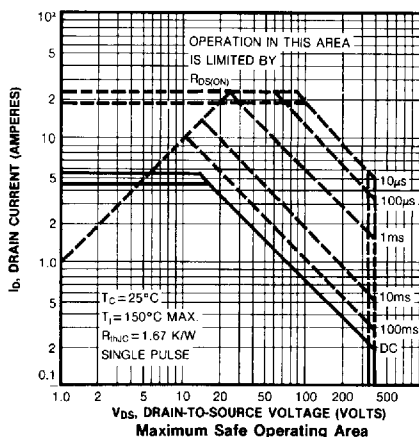
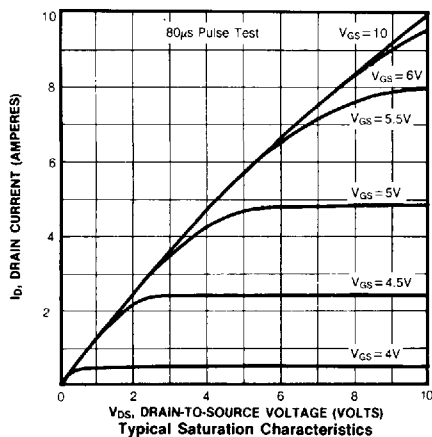
(3) Repetitive rating: Pulse width limited by max. junction temperature

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

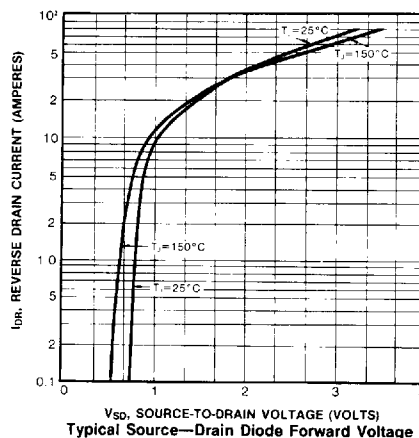
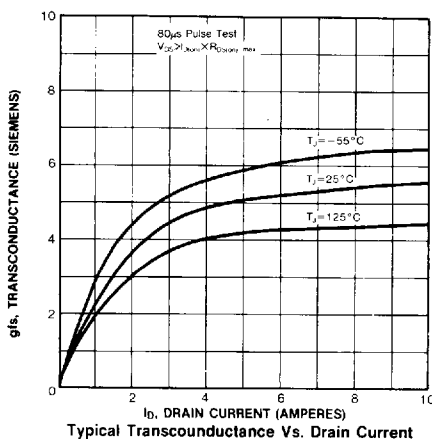
Symbol	Characteristic	Min	Typ	Max	Units	Test Conditions
I_S	Continuous Source Current (Body Diode) IRF730/IRFP330 IRF731/IRFP331	—	—	5.5	A	Modified MOSFET symbol showing the integral reverse P-N junction rectifier 
	IRF732/IRFP332 IRF733/IRFP333	—	—	4.5	A	
I_{SM}	Pulse Source Current(Body Diode)(3) IRF730/IRFP330/IRFP330 IRF731/IRFP331/IRFP331	—	—	22	A	
	IRF732/IRFP332 IRF733/IRFP333	—	—	18	A	
V_{SD}	Diode Forward Voltage (2) IRF730/IRFP330 IRF731/IRFP331	—	—	1.8	V	$T_C=25^\circ\text{C}$, $I_S=5.5\text{A}$, $V_{GS}=0\text{V}$
	IRF732/IRFP332 IRF733/IRFP333	—	—	1.6	V	$T_C=25^\circ\text{C}$, $I_S=4.5\text{A}$, $V_{GS}=0\text{V}$
t_{rr}	Reverse Recovery Time	—	310	660	ns	$T_J=25^\circ\text{C}$, $I_F=5.5\text{A}$, $dI_F/dt=100\text{A}/\mu\text{S}$

Notes: (1) $T_J=25^\circ\text{C}$ to 150°C (2) Pulse test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$
 (3) Repetitive rating: Pulse with limited by max. junction temperature





Maximum Effective Transient Thermal Impedance Junction-to-Case Vs. Pulse Duration



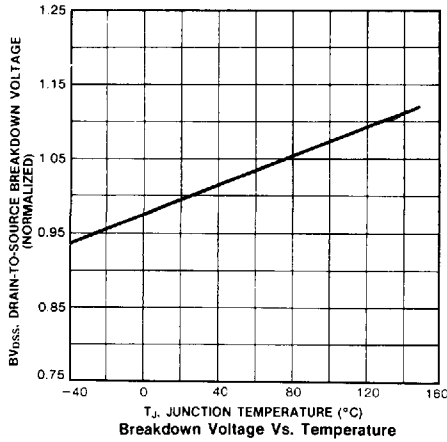
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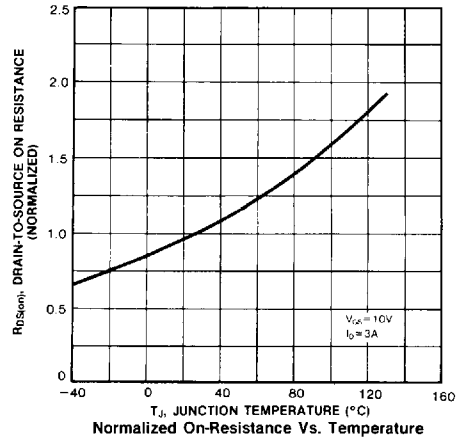
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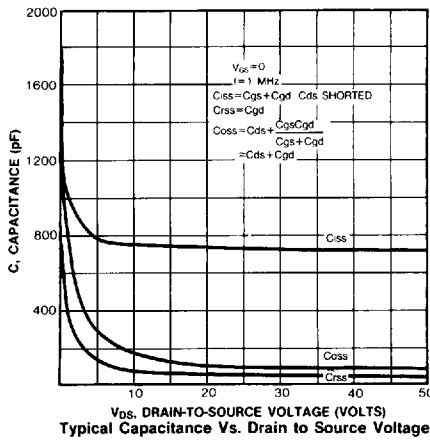
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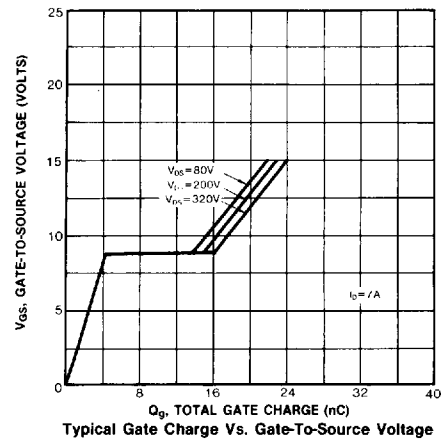
Breakdown Voltage Vs. Temperature



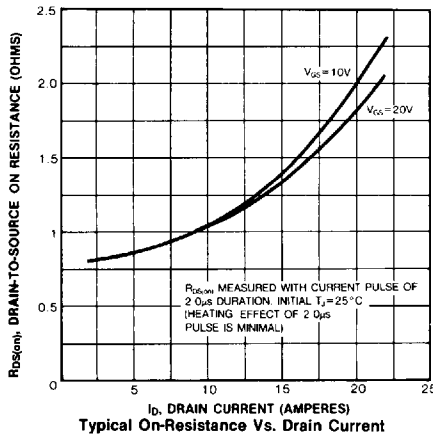
Normalized On-Resistance Vs. Temperature



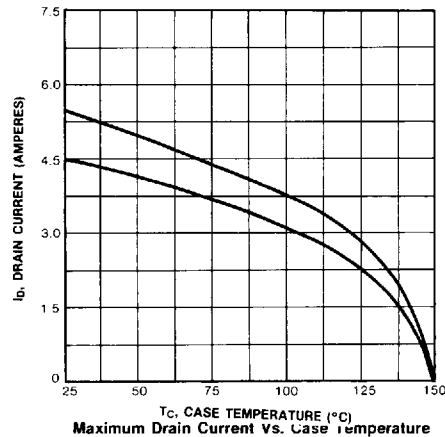
Typical Capacitance Vs. Drain to Source Voltage



Typical Gate Charge Vs. Gate-To-Source Voltage



Typical On-Resistance Vs. Drain Current



Maximum Drain Current Vs. Case temperature

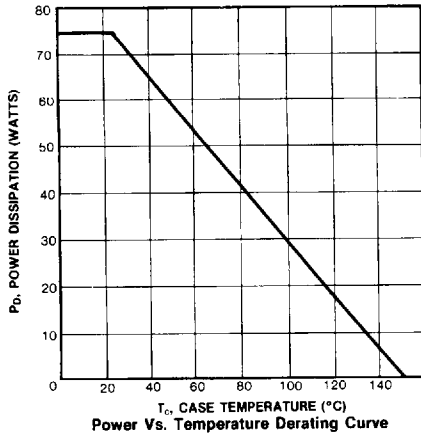
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